

# 4-Mbit (512 K × 8) Static RAM

#### **Features**

- Pin and function compatible with CY7C1049CV33
- High speed

  □ t<sub>AA</sub> = 10 ns
- Low active power
  □ I<sub>CC</sub> = 90 mA @ 10 ns (Industrial)
- Low CMOS standby power
  □ I<sub>SB2</sub> = 10 mA
- 2.0 V data retention
- Automatic power down when deselected
- TTL compatible inputs and outputs
- Easy memory expansion with CE and OE features
- Available in Pb-free 36-pin (400 Mil) Molded SOJ and 44-pin TSOP II packages

#### **Functional Description**

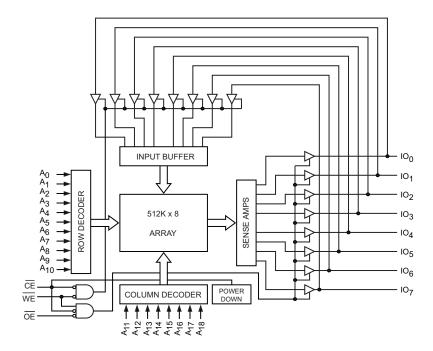
The CY7C1049DV33 is a high performance CMOS Static RAM organized as 512K words by 8-bits. Easy memory expansion is provided by an Active LOW Chip Enable ( $\overline{\text{CE}}$ ), an Active LOW Output Enable ( $\overline{\text{OE}}$ ), and tri-state drivers. You can write to the device by taking Chip Enable ( $\overline{\text{CE}}$ ) and Write Enable ( $\overline{\text{WE}}$ ) inputs LOW. Data on the eight IO pins (IO<sub>0</sub> through IO<sub>7</sub>) is then written into the location specified on the address pins (A<sub>0</sub> through A<sub>18</sub>).

You can read from the device by taking Chip Enable ( $\overline{CE}$ ) and Output Enable ( $\overline{OE}$ ) LOW while forcing Write Enable ( $\overline{WE}$ ) HIGH. Under these conditions, the contents of the memory location specified by the address pins appear on the IO pins.

The eight input or output pins ( $IO_0$  through  $IO_7$ ) are <u>placed</u> in a high impedance state whe<u>n</u> the device is deselected ( $\overline{CE}$  HIGH), the outputs are <u>disabled</u> ( $\overline{OE}$  HIGH), or during a write operation ( $\overline{CE}$  LOW, and  $\overline{WE}$  LOW).

The CY7C1049DV33 is available in standard 400 Mil wide 36 -pin SOJ package and 44-pin TSOP II package with center power and ground (revolutionary) pinout.

## Logic Block Diagram



## CY7C1049DV33



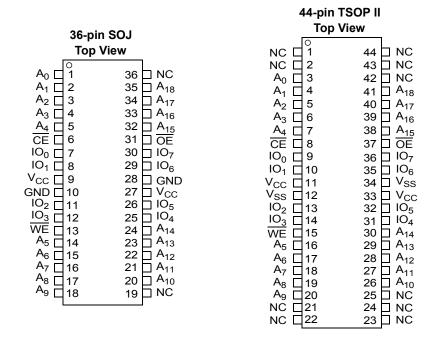
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## **Pin Configuration**



#### **Selection Guide**

	-10 (Industrial)	-12 (Automotive) <sup>[1]</sup>	Unit
Maximum Access Time	10	12	ns
Maximum Operating Current	90	95	mA
Maximum CMOS Standby Current	10	15	mA

#### Note

Automotive product information is preliminary.



## **Maximum Ratings**

Exceeding the maximum ratings may impair the useful life of the device. User guidelines are not tested.

Storage Temperature ......-65 °C to +150 °C

Ambient Temperature with

Power Applied ......–55 °C to +125 °C

Supply Voltage on  $V_{CC}$  to Relative  $\mbox{GND}^{[2]}$  .....–0.3 V to +4.6 V

DC Voltage Applied to Outputs in High Z State  $^{[2]}$  .....-0.3 V to V<sub>CC</sub> + 0.3 V

DC Input Voltage  $^{[2]}$  ......-0.3 V to V<sub>CC</sub> + 0.3 V

Operating Pange	
Latch up Current	> 200 mA
(MIL-STD-883, Method 3015)	
Static Discharge Voltage	>2001 V
Current into Outputs (LOW)	20 mA

## Operating Range

Range	Ambient Temperature	V <sub>cc</sub>	Speed
Industrial	–40 °C to +85 °C	$3.3~V\pm0.3~V$	10 ns
Automotive	–40 °C to +125 °C	$3.3~V\pm0.3~V$	12 ns

#### **Electrical Characteristics**

Over the Operating Range

				-10 (Inc	lustrial)	-12 (Aut	omotive)	
Parameter	Description	Test Condition	s	Min	Max	Min	Max	Unit
V <sub>OH</sub>	Output HIGH Voltage	V <sub>CC</sub> = Min, I <sub>OH</sub> = -4.0 m	A	2.4	_	2.4	_	V
V <sub>OL</sub>	Output LOW Voltage	V <sub>CC</sub> = Min, I <sub>OL</sub> = 8.0 mA		_	0.4	_	0.4	V
V <sub>IH</sub> <sup>[2]</sup>	Input HIGH Voltage			2.0	V <sub>CC</sub> + 0.3	2.0	V <sub>CC</sub> + 0.3	V
V <sub>IL</sub> [2]	Input LOW Voltage <sup>[2]</sup>			-0.3	0.8	-0.3	0.8	V
I <sub>IX</sub>	Input Leakage Current	$GND \leq V_I \leq V_CC$		-1	+1	<b>–</b> 1	+1	μΑ
I <sub>OZ</sub>	Output Leakage Current	GND ≤ V <sub>OUT</sub> ≤ V <sub>CC</sub> , Output Disabled		<b>–1</b>	+1	-1	+1	μА
I <sub>CC</sub>	V <sub>CC</sub> Operating Supply	V <sub>CC</sub> = Max,	100 MHz	_	90	_	-	mA
	Current	$f = f_{MAX} = 1/t_{RC}$	83 MHz	_	80	_	95	mA
			66 MHz	_	70	_	85	mA
			40 MHz	_	60	-	75	mA
I <sub>SB1</sub>	Automatic CE Power down Current —TTL Inputs			-	20	-	25	mA
I <sub>SB2</sub>	Automatic CE Power down Current —CMOS Inputs	$\begin{aligned} &\text{Max V}_{\text{CC}}, \overline{\text{CE}} \geq \text{V}_{\text{CC}} - 0.\\ &\text{V}_{\text{IN}} \geq \text{V}_{\text{CC}} - 0.3 \text{ V, or V}_{\text{IN}}\\ &\text{f} = 0 \end{aligned}$	3 V, ₁ ≤ 0.3 V,	-	10	-	15	mA

## Capacitance

Tested initially and after any design or process changes that may affect these parameters.

Parameter	Description	Test Conditions	Max	Unit
C <sub>IN</sub>	Input Capacitance	$T_A = 25 ^{\circ}\text{C}, f = 1 \text{MHz}, V_{CC} = 3.3 \text{V}$	8	pF
C <sub>OUT</sub>	IO Capacitance		8	pF

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<sup>2.</sup>  $V_{IL}$  (min.) = -2.0 V and  $V_{IH}$ (max) =  $V_{CC}$  + 2 V for pulse durations of less than 20 ns.



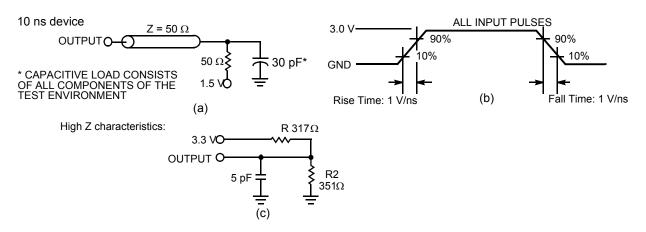
#### **Thermal Resistance**

Tested initially and after any design or process changes that may affect these parameters.

Parameter	Description	Test Conditions	36-pin SOJ Package	44-pin TSOP II Package	Unit
$\Theta_{JA}$		Still Air, soldered on a 3 × 4.5 inch, two layer printed circuit board	57.91	50.66	°C/W
Θ <sub>JC</sub>	Thermal Resistance (Junction to Case)		36.73	17.17	°C/W

#### **AC Test Loads and Waveforms**

Figure 1. AC Test Loads and Waveforms [4]

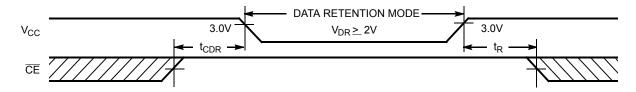


#### **Data Retention Characteristics**

Over the Operating Range

Parameter	Description	Conditions <sup>[5]</sup>		Min	Max	Unit
$V_{DR}$	V <sub>CC</sub> for Data Retention			2.0	-	V
I <sub>CCDR</sub>	Data Retention Current	$V_{CC} = V_{DR} = 2.0 \text{ V}, \overline{CE} \ge V_{CC} - 0.3 \text{ V}$	Industrial	_	10	mA
		$V_{IN} \ge V_{CC} - 0.3 \text{ V or } V_{IN} \le 0.3 \text{ V}$	Auto	-	15	mA
t <sub>CDR</sub> <sup>[3]</sup>	Chip Deselect to Data Retention Time			0	-	ns
t <sub>R</sub> <sup>[6]</sup>	Operation Recovery Time			t <sub>RC</sub>	-	ns

Figure 2. Data Retention Waveform



#### Notes

- Tested initially and after any design or process changes that may affect these parameters.
- AC characteristics (except High Z) are tested using the load conditions shown in Figure 1 (a). High Z characteristics are tested for all speeds using the test load shown in Figure 1 (c).
- No input may exceed  $V_{\rm CC}$  + 0.3 V.
- Full device operation requires linear V<sub>CC</sub> ramp from V<sub>DR</sub> to V<sub>CC(min.)</sub>  $\geq$  50  $\mu$ s or stable at V<sub>CC(min.)</sub>  $\geq$  50  $\mu$ s.

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## **AC Switching Characteristics**

Over the Operating Range [7]

		-10 (Inc	dustrial)	-12 (Automotive)		
Parameter	Description	Min	Max	Min	Max	Unit
Read Cycle		<u>'</u>	·	•	•	•
t <sub>power</sub> <sup>[8]</sup>	V <sub>CC</sub> (typical) to the first access	100	_	100	_	μS
t <sub>RC</sub>	Read Cycle Time	10	-	12	_	ns
t <sub>AA</sub>	Address to Data Valid	_	10	-	12	ns
t <sub>OHA</sub>	Data Hold from Address Change	3	_	3	_	ns
t <sub>ACE</sub>	CE LOW to Data Valid	_	10	_	12	ns
t <sub>DOE</sub>	OE LOW to Data Valid	_	5	_	6	ns
t <sub>LZOE</sub>	OE LOW to Low Z <sup>[9]</sup>	0	_	0	_	ns
t <sub>HZOE</sub>	OE HIGH to High Z <sup>[9, 10]</sup>	_	5	_	6	ns
t <sub>LZCE</sub>	CE LOW to Low Z <sup>[9]</sup>	3	_	3	-	ns
t <sub>HZCE</sub>	CE HIGH to High Z <sup>[9, 10]</sup>	_	5	_	6	ns
t <sub>PU</sub>	CE LOW to Power up	0	_	0	-	ns
t <sub>PD</sub>	CE HIGH to Power down	_	10	1	12	ns
Write Cycle	11, 12]		_			
t <sub>WC</sub>	Write Cycle Time	10	_	12	-	ns
t <sub>SCE</sub>	CE LOW to Write End	7	_	8	_	ns
t <sub>AW</sub>	Address Set up to Write End	7	_	8	-	ns
t <sub>HA</sub>	Address Hold from Write End	0	_	0	_	ns
t <sub>SA</sub>	Address Set up to Write Start	0	_	0	_	ns
t <sub>PWE</sub>	WE Pulse Width	7	-	8	-	ns
t <sub>SD</sub>	Data Set up to Write End	5	-	6	_	ns
t <sub>HD</sub>	Data Hold from Write End	0	_	0	_	ns
t <sub>LZWE</sub>	WE HIGH to Low Z <sup>[9]</sup>	3	_	3	_	ns
t <sub>HZWE</sub>	WE LOW to High Z <sup>[9, 10]</sup>	_	5	-	6	ns

#### Notes

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Test conditions assume signal transition time of 3 ns or less, timing reference levels of 1.5 V, input pulse levels of 0 to 3.0 V, and output loading of the specified I<sub>OL</sub>/I<sub>OH</sub> and 30 pF load capacitance.

and 30 pF load capacitance.

8. t<sub>POWER</sub> gives the minimum amount of time that the power supply must be at stable, typical V<sub>CC</sub> values until the first memory access is performed.

9. At any temperature and voltage condition, t<sub>HZCE</sub> is less than t<sub>LZCE</sub>, t<sub>HZOE</sub> is less than t<sub>LZOE</sub>, and t<sub>HZWE</sub> is less than t<sub>LZWE</sub> for any given device.

10. t<sub>HZOE</sub>, t<sub>HZCE</sub>, and t<sub>HZWE</sub> are specified with a load capacitance of 5 pF as in part (c) of Figure 1 on page 5. Transition is measured when the outputs enter a high impedance state.

11. The internal write time of the memory is defined by the overlap of CE LOW, and WE LOW. CE and WE must be LOW to initiate a write, and the transition of either of these signals can terminate the write. The input data set up and hold timing must be referred to the leading edge of the signal that terminates the write.

12. The minimum write cycle time for Write Cycle No. 2 (WE controlled, OE LOW) is the sum of t<sub>HZWE</sub> and t<sub>SD</sub>.



## **Switching Waveforms**

Figure 3. Read Cycle No. 1<sup>[13, 14]</sup>

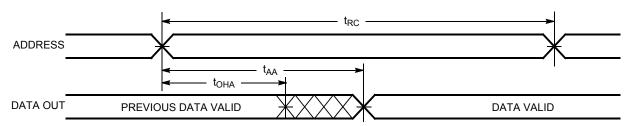


Figure 4. Read Cycle No. 2 (OE Controlled)[14, 15]

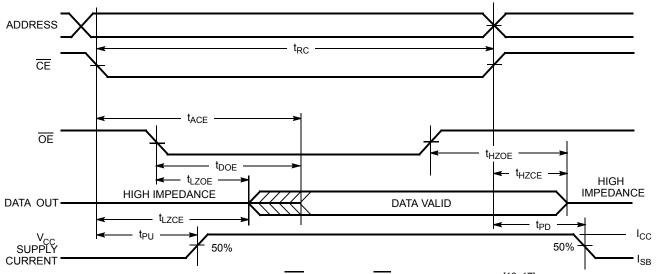
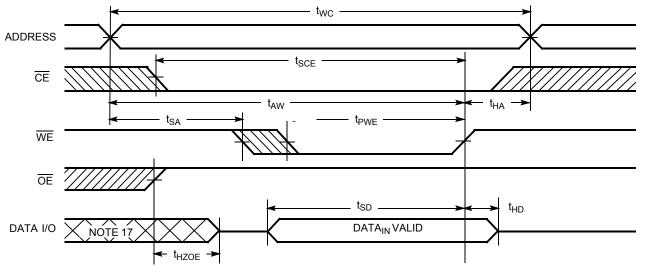


Figure 5. Write Cycle No. 1 (WE Controlled, OE HIGH During Write)[16, 17]



#### Notes

- 13. <u>Dev</u>ice is continuously selected. <del>OE</del>, <del>CE</del> = V<sub>IL</sub>.

  14. WE is HIGH for read cycle.

  15. Address valid prior to or coin<u>cident with <del>CE</del> transition LOW.</u>

  16. <u>Data</u> IO is high impedance if <del>OE</del> = V<sub>IL</sub>.

  17. If <del>CE</del> goes HIGH simultaneously with WE going HIGH, the output remains in a high impedance state.



## Switching Waveforms (continued)

Figure 6. Write Cycle No. 2 (WE Controlled, OE LOW)[18]

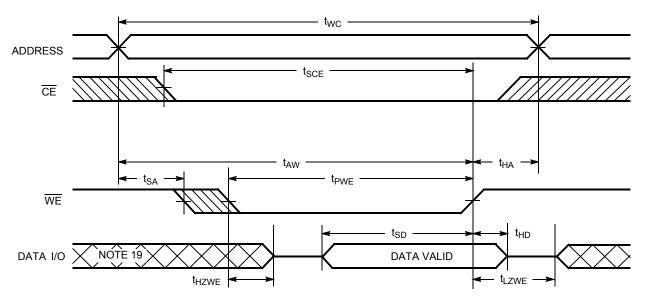
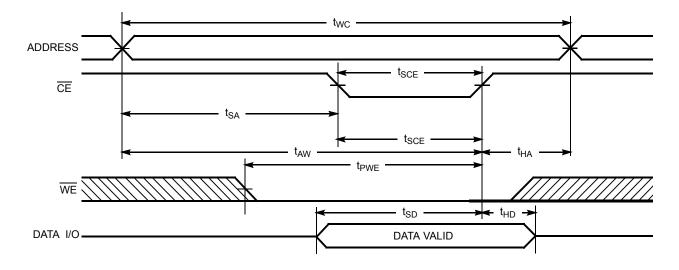


Figure 7. Write Cycle No. 3 ( $\overline{\text{CE}}$  Controlled)[18, 20]



<sup>18.</sup> If CE goes HIGH simultaneously with WE going HIGH, the output remains in a high impedance state.

19. During this period the IOs are in the output state and input signals must not be applied.

20. Data IO is high impedance if OE = V<sub>IH</sub>.



### **Truth Table**

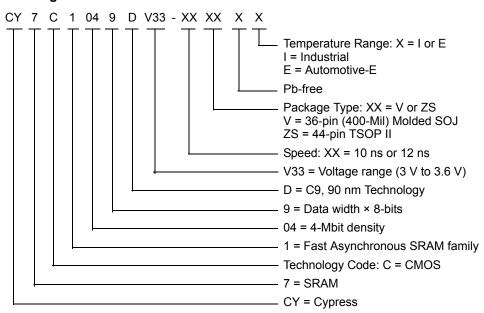
CE	OE	WE	IO <sub>0</sub> –IO <sub>7</sub>	Mode	Power
Н	Х	Х	High Z	Power down	Standby (I <sub>SB</sub> )
L	L	Н	Data Out	Read	Active (I <sub>CC</sub> )
L	Х	L	Data In	Write	Active (I <sub>CC</sub> )
L	Н	Н	High Z	Selected, Outputs Disabled	Active (I <sub>CC</sub> )

## **Ordering Information**

Speed (ns)	Ordering Code	Package Name	Package Type	Operating Range
10	CY7C1049DV33-10VXI	51-85090	36-pin (400-Mil) Molded SOJ (Pb-free)	Industrial
	CY7C1049DV33-10ZSXI	51-85087	44-pin TSOP II (Pb-free)	
12	CY7C1049DV33-12VXE	51-85090	36-pin (400-Mil) Molded SOJ (Pb-free)	Automotive
	CY7C1049DV33-12ZSXE	51-85087	44-pin TSOP II (Pb-free)	

Contact your local Cypress sales representative for availability of these parts.

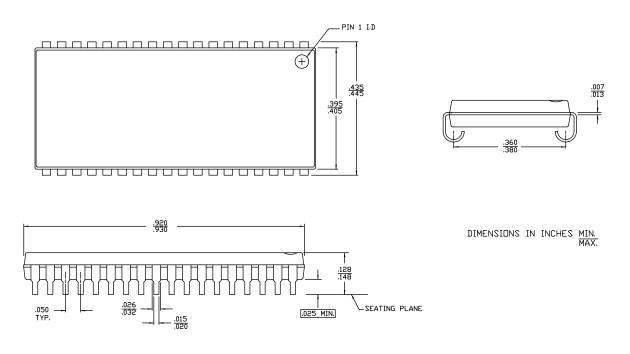
#### **Ordering Code Definitions**





## **Package Diagrams**

Figure 8. 36-pin (400-Mil) Molded SOJ V36.4, (51-85090)

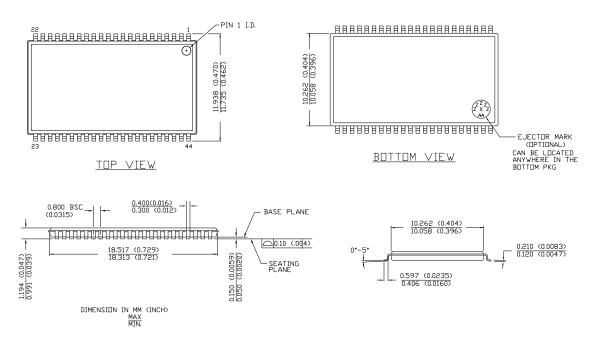


51-85090 \*E



## Package Diagrams (continued)

Figure 9. 44-pin TSOP Z44-II, (51-85087)



51-85087 \*C



## **Acronyms**

Acronym	Description			
CE	chip enable			
CMOS	complementary metal oxide semiconductor			
I/O	input/output			
OE	output enable			
SOJ	small outline J-lead			
SRAM	static random access memory			
TSOP	thin small outline package			
TTL	transistor-transistor logic			
WE	write enable			

## **Document Conventions**

#### **Units of Measure**

Symbol	Unit of Measure		
°C	degree Celcius		
MHz	Mega Hertz		
μΑ	micro Amperes		
μs	micro seconds		
mA	milli Amperes		
mm	milli meter		
ms	milli seconds		
ns	nano seconds		
Ω	ohms		
%	percent		
pF	pico Farad		
V	Volts		
W	Watts		



## **Document History Page**

REV.	ECN NO.	Issue Date	Orig. of Change	Description of Change
**	201560	See ECN	SWI	Advance Datasheet for C9 IPP
*A	233729	See ECN	SYT	1.AC, DC parameters are modified as per EROS (Specification # 01-2165) 2.Pb-free offering in the Ordering Information Table
*B	351096	See ECN	PCI	Changed from Advance to Preliminary Removed 20 ns Speed bin Corrected DC voltage (min) value in maximum ratings section from - 0.5 to - 0.3 Redefined I $_{CC}$ values for Com'l and Ind'l temperature ranges I $_{CC}$ (Com'l): Changed from 100, 80, and 67 mA to 90, 80 and, 75 mA for 8, 10, and 12ns speed bins respectively I $_{CC}$ (Ind'l): Changed from 80 and 67 mA to 90 and 85 mA for 10 and 12ns speed bins respectively Added V $_{IH(max)}$ specification in Note# 2 Changed reference voltage level for measurement of High Z parameters from $\pm$ 500 mV to $\pm$ 200 mV Added Data Retention Characteristics, Waveform, and footnotes 11 and 12 Changed Package Diagram name from 44-pin TSOP II Z44 to 44-pin TSOP II Z540 Changed part names from Z to ZS in the Ordering Information Table Added Pb-free Ordering Information Table Shaded Ordering Information Table
*C	446328	See ECN	NXR	Converted from Preliminary to Final Removed -8 speed bin Removed Commercial Operating Range product information Added Automotive Operating Range product information Updated Thermal Resistance table Updated footnote #8 on High Z parameter measurement Replaced Package Name column with Package Diagram in the Ordering Information table
*D	1274726	See ECN	VKN/AESA	Corrected typo in the 44-Pin TSOP II pinout
*E	2899972	03/29/2010	AJU	Updated Package Diagrams.
*F	3059162	10/14/2010	PRAS	Added Ordering Code Definitions. Updated Package Diagrams.
*G	3266084	05/28/2011	PRAS	Updated Functional Description (Removed "Refer to the Cypress application note AN1064, SRAM System Guidelines for best practice recommendations."). Added Acronyms and Units of Measure. Updated in new template.

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